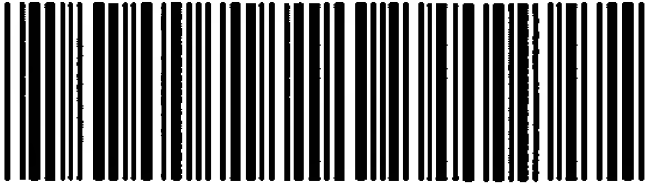


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/776,191	MADISON ET AL.	
	Examiner	Art Unit	
	Yong D. Pak	1652	

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Class	Subclass	Date	Examiner
435	212	4/13/2006	YP
435	440	4/13/2006	YP
435	69.1	4/13/2006	YP
435	71.1	4/13/2006	YP
536	23.2	4/13/2006	YP
536	23.5	4/13/2006	YP

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
stic: seq di no:2	4/13/2006	YP
inventor search	4/13/2006	YP
updated search	4/13/2006	YP